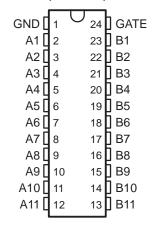
- Designed to be Used in Voltage-Limiting Applications
- 6.5-Ω On-State Connection Between Ports A and B
- Flow-Through Pinout for Ease of Printed Circuit Board Trace Routing
- Direct Interface With GTL+ Levels
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DBQ), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

# description

The SN74TVC3010 provides 11 parallel NMOS pass transistors with a common gate. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

# DBQ, DGV, DW, OR PW PACKAGE (TOP VIEW)



The device can be used as a 10-bit switch with the gates cascaded together to a reference transistor. The low-voltage side of each pass transistor is limited to a voltage set by the reference transistor. This is done to protect components with inputs that are sensitive to high-state voltage-level overshoots. (See Application Information in this data sheet.)

All of the transistors in the TVC array have the same electrical characteristics; therefore, any one of them can be used as the reference transistor. Since, within the device, the characteristics from transistor to transistor are equal, the maximum output high-state voltage ( $V_{OH}$ ) is approximately the reference voltage ( $V_{REF}$ ), with minimum deviation from one output to another. This is a large benefit of the TVC solution over discrete devices. Because the fabrication of the transistors is symmetrical, either port connection of each bit can be used as the low-voltage side, and the I/O signals are bidirectional through each FET.

The SN74TVC3010 is characterized for operation from –40°C to 85°C.

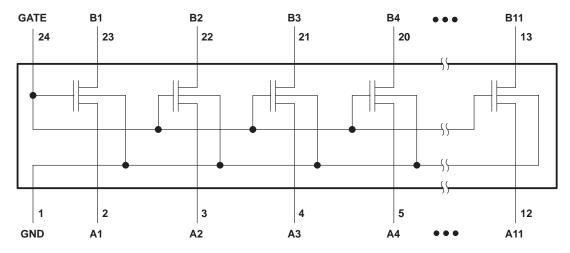


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# simplified schematic



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Input voltage range, V <sub>I</sub> (see Note 1)		0.5 V to 7 V
Input/output voltage range, V <sub>I/O</sub> (see Note 1) .		. −0.5 V to 7 V
Continuous channel current		128 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)		–50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2):	DBQ package	103°C/W
	DGV package	139°C/W
	DW package	81°C/W
	PW package	120°C/W
Storage temperature range, T <sub>stg</sub>		-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		MIN	TYP	MAX	UNIT
V <sub>I/O</sub>	Input/output voltage	0		5	V
VGATE	GATE voltage	0		5	V
IPASS	Pass-transistor current		20	64	mA
TA	Operating free-air temperature	-40		85	°C

# application operating conditions (see Figure 3)

		MIN	TYP	MAX	UNIT
VBIAS	BIAS voltage	V <sub>REF</sub> + 0.6	2.1	5	V
VGATE	GATE voltage	V <sub>REF</sub> + 0.6	2.1	5	V
VREF	Reference voltage	0	1.5	4.4	V
V <sub>DPU</sub>	Drain pullup voltage	2.36	2.5	2.64	V
IPASS	Pass-transistor current		14		mA
IREF	Reference-transistor current		5		μΑ
TA	Operating free-air temperature	-40		85	°C



NOTES: 1. The input and input/output negative-voltage ratings may be exceeded if the input and input/output clamp-current ratings are observed.

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP <sup>†</sup>	MAX	UNIT	
VIK	V <sub>BIAS</sub> = 0,	I <sub>I</sub> = -18 mA				-1.2	V
V <sub>OL</sub>	I <sub>REF</sub> = 5 μA, V <sub>DPU</sub> = 2.625 V,	$V_{REF} = 1.365 \text{ V},$ $R_{DPU} = 150 \Omega,$	$V_S = 0.175 V$ , (see Figure 1)			350	mV
C <sub>i(GATE)</sub>	V <sub>I</sub> = 3 V or 0				24		pF
C <sub>io(OFF)</sub>	$V_O = 3 V \text{ or } 0$				4	12	pF
C <sub>io(ON)</sub>	$V_O = 3 V \text{ or } 0$				12	30	pF
r <sub>on</sub> ‡	I <sub>REF</sub> = 5 μA, V <sub>DPU</sub> = 2.625 V,	$V_{REF} = 1.365 \text{ V},$ $R_{DPU} = 150 \Omega,$	$V_S = 0.175 V$ , (see Figure 1)			12.5	Ω

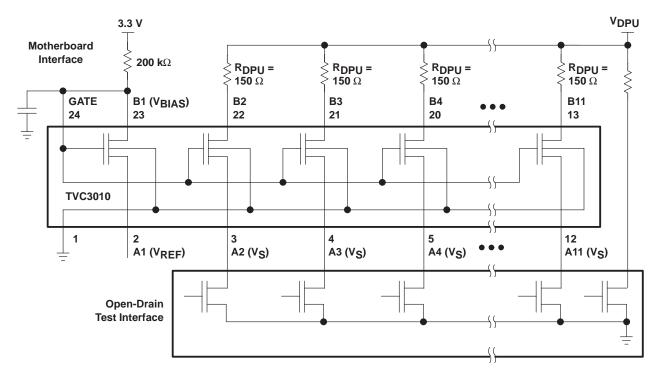
<sup>†</sup> All typical values are at  $T_A = 25$ °C.

# switching characteristics over recommended operating free-air temperature range, $V_{DPU}$ = 2.36 V to 2.64 V (unless otherwise noted) (see Figure 1)

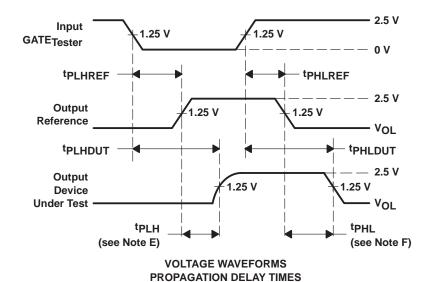
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
t <sub>PLH</sub>	A = = B	B or A	0	4	
<sup>t</sup> PHL	A or B		0	4	ns

<sup>&</sup>lt;sup>‡</sup> Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two (A or B) terminals.

#### PARAMETER MEASUREMENT INFORMATION



**TESTER CALIBRATION SETUP (see Note D)** 



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq 2$  ns,  $t_f \leq 2$  ns.
- C. The outputs are measured one at a time with one transition per measurement.
- D. Test procedure: tp\_HREF and tpHLREF are obtained by measuring the propagation delay of a reference measuring point. tp\_HDUT and tpHLDUT are obtained by measuring the propagation delay of the device under test.
- E. tplH = tplHDUT tplHREF
- F. tphl = tphldut tphlref

Figure 1. Tester Calibration Setup and Voltage Waveforms



## TVC background information

In personal computer (PC) architecture there are industry-accepted bus standards. These standards define, among other things, the I/O voltage levels at which the bus communicates. Examples include the GTL+ host bus, the AGP graphics port, and the PCI local bus. In new designs, the system components must communicate with existing bus infrastructure. Providing an evolutionary upgrade path is important in the design of PC architecture, but the existing bus standards must be preserved.

To achieve the ever-present needs for smaller, faster, lighter devices that draw less power, yet have faster performance, most new high-performance digital integrated circuits are being designed and produced with advanced submicron semiconductor process technologies. These devices have thin gate-oxide or short channel lengths and very low absolute-maximum voltages that can be tolerated at the inputs/outputs (I/Os) without causing damage. In many cases, the I/Os of these devices are not tolerant of the high-state voltage-levels on the pre-existing buses with which they must communicate. Therefore, the need arose for protection of the I/Os of devices by limiting the I/O voltages.

The Texas Instruments (TI™) Translation Voltage Clamp (TVC) family was designed for the specific application of protecting sensitive I/Os (see Figure 2). The information in this data sheet describes the I/O protection application of the TVC family and should enable the design engineer to successfully implement an I/O protection circuit utilizing the TI TVC solution.

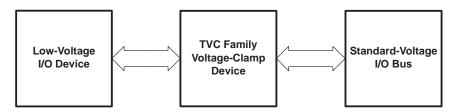
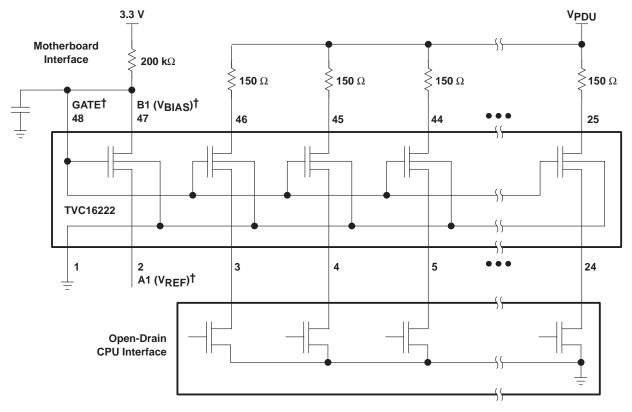


Figure 2. Thin Gate-Oxide Protection Application

## TVC voltage-limiting application

For the voltage-limiting configuration, the common GATE input must be connected to one side (A or B) of any one of the transistors (see Figure 3). This connection determines the  $V_{BIAS}$  input of the reference transistor. The  $V_{BIAS}$  input is connected through a pullup resistor (typically,  $200\,\mathrm{k}\Omega$ ) to the  $V_{DD}$  supply. A filter capacitor on  $V_{BIAS}$  is recommended. The opposite side of the reference transistor is used as the reference voltage ( $V_{REF}$ ) connection. The  $V_{REF}$  input must be less than  $V_{DD}-1$  V to bias the reference transistor into conduction. The reference transistor regulates the gate voltage ( $V_{G}$ ) of all the pass transistors.  $V_{G}$  is determined by the characteristic gate-to-source voltage difference ( $V_{GS}$ ) because  $V_{G}=V_{REF}+V_{GS}$ . The low-voltage side of the pass transistors has a high-level voltage limited to a maximum of  $V_{G}-V_{GS}$ , or  $V_{REF}$ .



TVREF and VBIAS can be applied to any one of the pass transistors. GATE must be connected externally to VBIAS.

**Figure 3. Typical Application Circuit** 



#### electrical characteristics

The electrical characteristics of the NMOS transistors used in the TVC devices are illustrated by TI SPICE simulations. Figure 4 shows the test configuration for the TI SPICE simulations. The results, shown in Figures 5 and 6, show the current through a pass transistor, versus the voltage at the source for different reference voltages. The plots of the dc characteristics clearly reveal that the device clamps at the desired reference voltage for the varying device environments.

Figure 5 shows the V-I characteristics, with low reference voltages and a reference-transistor drain-supply voltage of 3.3 V. To further investigate the spread of the V-I characteristic curves,  $V_{REF}$  was held at 2.5 V and  $I_{REF}$  was increased by raising  $V_{DDREF}$  (see Figure 6). The result was a tighter grouping of the V-I curves.

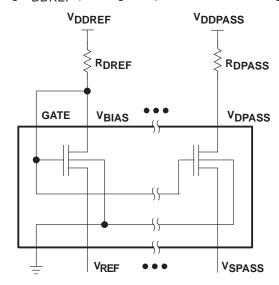


Figure 4. TI SPICE Simulation Schematic and Voltage-Node Names

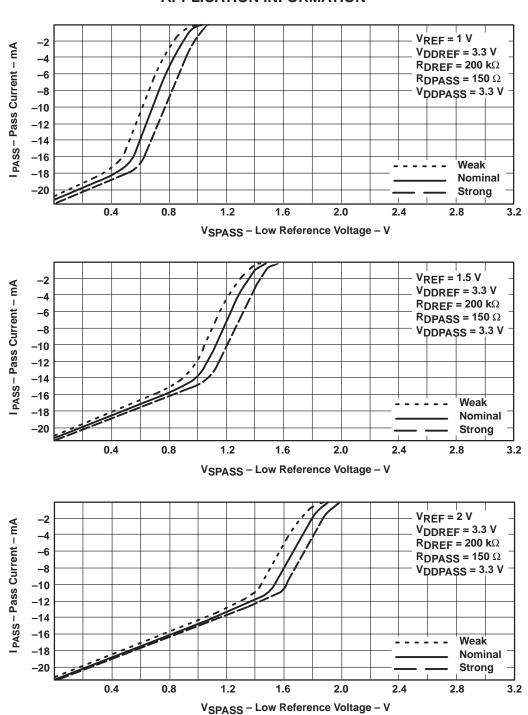


Figure 5. Electrical Characteristics at Low V<sub>REF</sub> Voltages



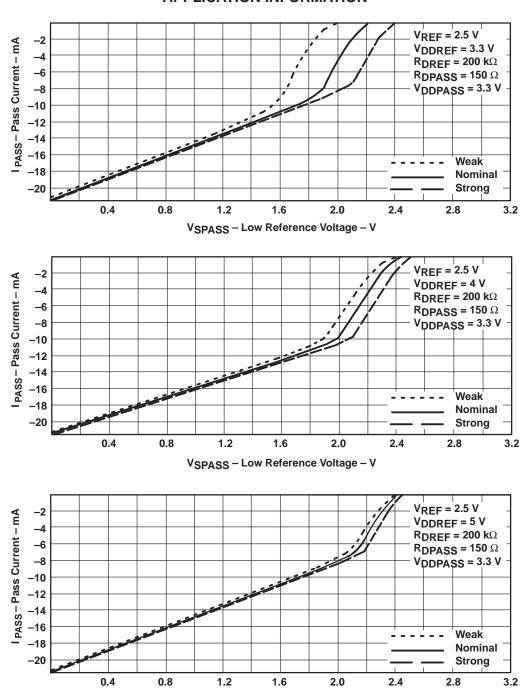


Figure 6. Electrical Characteristics at V<sub>REF</sub> = 2.5 V

VSPASS - Low Reference Voltage - V



#### features and benefits

The TVC family has several features that benefit a system designer when implementing a sensitive-I/O protection solution. Table 1 lists these features and their associated benefits.

Table 1. Features and Benefits

FEATURES	BENEFITS
Any FET can be used as the reference transistor.	Ease of layout
All FETs on one die, tight process control	Very low spread of VO relative to VREF
No active control logic (passive device)	No logic power supply (V <sub>CC</sub> ) required
Flow-through pinout	Ease of trace routing
Devices offered in different bit-widths and packages	Optimizes design and cost effectiveness
Designer flexibility with V <sub>REF</sub> input	Allows migration to lower-voltage I/Os without board redesign

#### conclusion

The TI TVC family provides the designer with a solution for protection of circuits with I/Os that are sensitive to high-state voltage-level overshoots. The flexibility of TVC enables a low-voltage migration path for advanced designs to align with industry standards.

# frequently asked questions (FAQ)

- 1. Q: Can any of the transistors in the array be used as the reference transistor?
  - A: Yes, any transistor can be used as long as its V<sub>BIAS</sub> pin is connected to the GATE pin.
- Q: In the recommended operating conditions table of the data sheet, the typical V<sub>BIAS</sub> is 3.3 V. Should V<sub>BIAS</sub> be equal to or greater than V<sub>REF</sub> on the reference transistor?
  - A:  $V_{BIAS}$  is a variable that is determined by  $V_{REF}$ .  $V_{BIAS}$  is connected to  $V_{DD}$  through a resistor to allow the bias voltage to be controlled by  $V_{REF}$ .  $V_{DD}$  can be as high as 5.5 V.  $V_{REF}$  needs to be at least 1 V less than  $V_{BIAS}$  on the reference transistor.
- 3. Q: Do both A and B ports have 5-V I/O tolerance or is 5-V I/O tolerance provided only on the low-voltage side?
  - A: Both ports are 5-V tolerant.



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